TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ($L^2-\pi$ -MOSV)

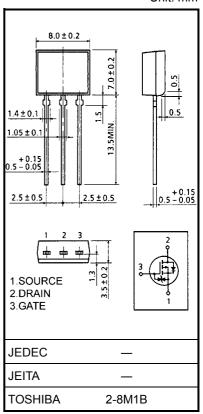
2SJ378

Relay Drive, DC–DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance $R_{DS}(ON) = 0.16 \Omega$ (typ.)
- High forward transfer admittance $|Y_{fs}| = 4.0 \text{ S (typ.)}$
- Low leakage current $: I_{DSS} = -100 \ \mu A \ (max) \ (V_{DS} = -60 \ V)$
- Enhancement-mode : $V_{th} = -0.8 \sim -2.0 V (V_{DS} = -10 V, I_D = -1 mA)$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	-60	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V _{DGR}	-60	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	۱ _D	-5	А	
	Pulse(Note 1)	I _{DP}	-20	А	
Drain power dissipatio	n	PD	1.3	W	
Single pulse avalanche energy (Note 2)		E _{AS}	273	mJ	
Avalanche current		I _{AR}	-5	А	
Repetitive avalenche energy (Note 3)		E _{AR}	0.13	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 0.54 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R _{th (ch−a)}	96.1	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = -25 V, T_{ch} = 25°C (initial), L = 14.84 mH, R_G = 25 Ω , I_{AR} = -5 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution. Unit: mm

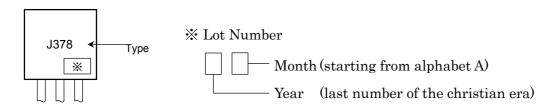
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V		_	±10	μA
Drain cut-off cu	rrent	I _{DSS}	$V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$	_		-100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = -10 mA, V _{GS} = 0 V	-60	_	_	V
Gate threshold v	voltage	V _{th}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8		-2.0	V
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = -4 V, I _D = -2.5 A	_	0.24	0.28	Ω
			V_{GS} = -10 V, I _D = -2.5 A	_	0.16	0.19	32
Forward transfe	r admittance	Y _{fs}	V_{DS} = -10 V, I _D = -2.5 A	2.0	4.0	—	S
Input capacitance	ce	C _{iss}		-	630	_	
Reverse transfer capacitance		C _{rss}		_	95	_	pF
Output capacitance		Coss			290	_	
Switching time	Rise time	tr	$V_{\rm GS} \stackrel{\rm OV}{\sim}$	_	25	_	
	Turn-on time	t _{on}	$V_{GS} \stackrel{0V}{\xrightarrow{-10V}} \stackrel{I_{D} = -2.5A}{} V_{OUT}$ $R_{L} = 12\Omega$ $V_{DD} = -30V$	_	45	_	20
	Fall time	t _f		_	55	_	- ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, t _w =10 μ s	_	200	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	22	_	
Gate-source charge		Q _{gs}	V _{DD} ≈ -48 V, V _{GS} = -10 V, I _D = -5 A	_	16	_	nC
Gate-drain ("miller") charge		Q _{gd}			6	_	

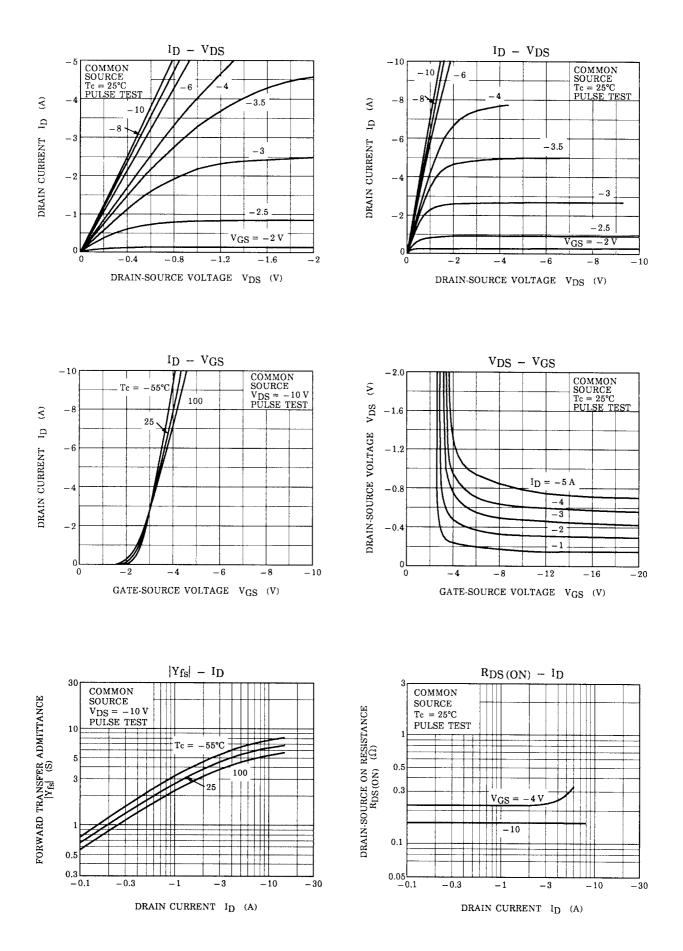
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	-5	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_	_	-20	А
Forward voltage (diode)	V _{DSF}	I _{DR} = -5 A, V _{GS} = 0 V	_	_	1.7	V
Reverse recovery time	t _{rr}	I _{DR} = −5 A, V _{GS} = 0 V dI _{DR} / dt = 50 A / μS		80		ns
Reverse recovery charge	Qrr		_	0.1	_	μC

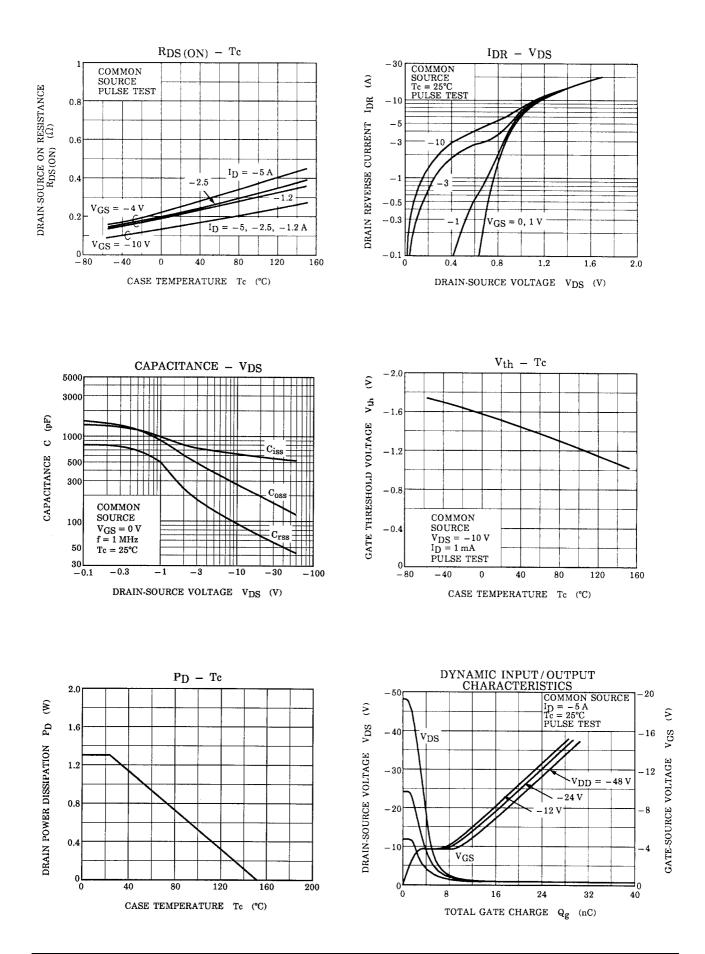
Marking

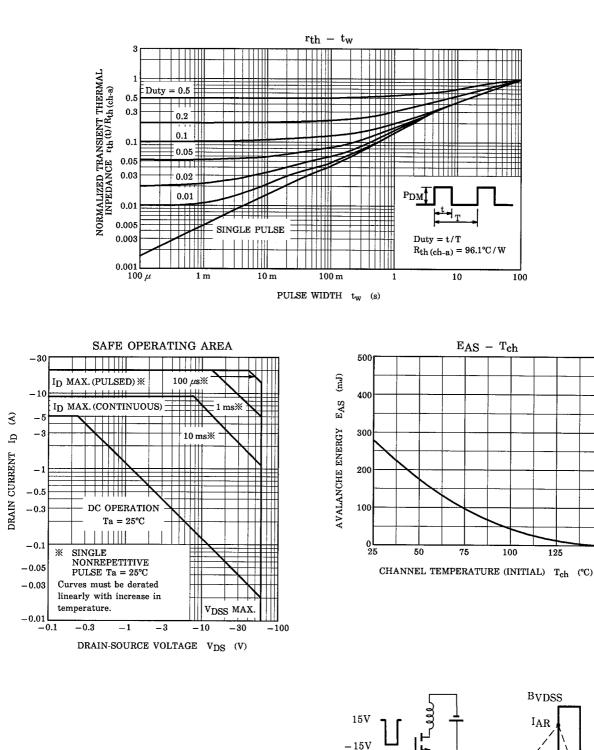


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VDS

 v_{DD}

WAVE FORM

 $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}}\right)$

TEST CIRCUIT

 $V_{DD} = -25V, L = 14.84mH$

150

 $R_G = 25\Omega$

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